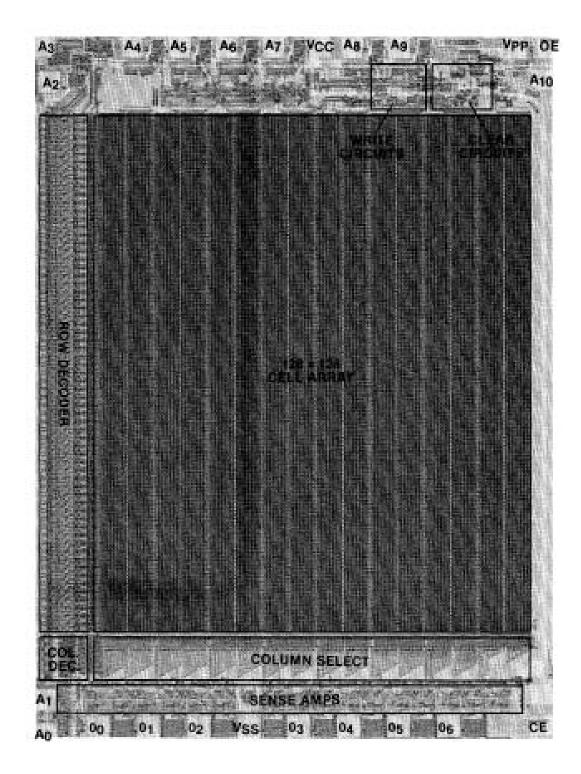
FIRST 16KB FLOTOX EEPROM

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A 16KB Electrically Erasable Nonvolatile Memory

IN 1980, JOHNSON et al. (Intel) described an electrically erasable nonvolatile memory. This device used a Floating Gate Tunnel Oxide (FLOTOX) two transistor cell. The cell size was 0.85 mil^2 using 3.5 μm

technology. Tunnel oxide thickness was less than 200 Angstrom, and

endurance of more than 10^5 cycles was reported. This cell and the design

techniques were widely adopted by the industry on many other memories.

W.S. Johnson, G. Perlegos, A. Renninger, G. Kuhn, T.R. Ranganath Intel Corp., Santa Clara, CA